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Contents

Part One

xvii  Conference Committee
xix  Symposium Committees
xxi  Introduction

SESSION 3-1

7283 02  Calibration of rotary joints in multi-axis machine tools  [7283-01]
   A. W. Khan, F. Liu, W. Chen, Beihang Univ. (China)

7283 03  Development of a parallelism tester for visible and infrared compound system  [7283-02]
   H. Jing, S. Wu, Q. Chen, B. Lei, J. Jiang, K. Mei, Institute of Optics and Electronics (China)

7283 04  Micro assembled Fourier transform spectrometer  [7283-03]
   Y. Kong, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate
   School of the Chinese Academy of Sciences (China); J. Liang, Z. Liang, Changchun Institute
   of Optics, Fine Mechanics and Physics (China); B. Wang, Changchun Institute of Optics, Fine
   Mechanics and Physics (China) and Graduate School of the Chinese Academy of Sciences
   (China); J. Zhang, Jinan Univ. (China)

7283 05  Non-null interferometric system for general aspheric test  [7283-04]
   D. Liu, Y. Yang, C. Tian, L. Wang, Y. Zhuo, Zhejiang Univ. (China)

7283 06  Study on data processing and experiment of Fabry-Perot fiber optic strain gauge  [7283-05]
   H. Wang, Chongqing Technology and Business Univ. (China); J. Jiang, Chongqing Jiaotong
   Univ. (China); Y. Lu, Chongqing Technology and Business Univ. (China)

7283 07  Real-time portable dual channel image fusion and data processing system  [7283-06]
   L. Wang, Y. Yang, D. Wang, D. Liu, Zhejiang Univ. (China)

7283 08  Pyroelectric property of novel LiTa3O8 thin film prepared by sol-gel methods  [7283-07]
   D.-Y. Zhang, Civil Aviation Flight Univ. of China (China)

7283 09  Measurement of phase noise through beat frequency  [7283-08]
   Y. He, R. Zhang, Sichuan Univ. (China)

7283 0A  Alignment of off-axis asphere and compensator with four poles  [7283-09]
   B. Xuan, X. Chen, P. Wang, J. Li, Changchun Institute of Optics, Fine Mechanics and Physics
   (China) and Graduate School of the Chinese Academy of Sciences (China); S. Song,
   Y. Chen, J. Xie, Changchun Institute of Optics, Fine Mechanics and Physics (China)

7283 0B  Quantitative characterization of supersmooth surface with roughness in the sub-nanometer
   range  [7283-10]
   Z. Shen, Z. Wang, B. Ma, L. Wang, Tongji Univ. (China); Y. Ji, H. Liu, Tianjin Jinhang Institute
   of Technology Physics (China)
Tracking and detecting occupational diseases for teachers with infrared imaging method [7283-11]
S. Chen, S. An, S. Wang, Hebei Univ. of Science & Technology (China)

Stabilization of a multiplexed optical fiber interferometer system [7283-12]
X. Fang, J. Jia, Z. Chen, Beijing Jiaotong Univ. (China)

SESSION 3-2

Dynamic liquid surface shape measurement [7283-13]
X. Wu, Nanjing Univ. of Information Science & Technology (China); L. Chen, Nanjing Univ. of Science & Technology (China); Z. Tao, Nanjing Univ. of Information Science & Technology (China)

Alignment error model of subaperture stitching interferometry for aspheric surface based on wavefront aberrations [7283-14]
W. Wang, J. Tan, L. Zhu, Z. Ge, Harbin Institute of Technology (China)

Large dynamic range optical metrology with radial shearing interferometry [7283-15]
D. Li, X. Qi, Y. Cao, X. Zhou, Q. Wang, Sichuan Univ. (China)

AGV trace sensing and processing technology based on RGB color sensor array [7283-16]
K. Xu, P. Zhu, Shandong Univ. of Science and Technology (China); J. Wang, Shandong Academy of Sciences (China); Y. Yun, Qingdao Agricultural Univ. (China)

New method of annular sub-apertures stitching [7283-17]
Y. Su, K. Wang, N. Ruan, B. Li, Beijing Institute of Space Mechanics & Electricity (China)

Study on multi-sensor optic-electrical system performance test [7283-18]
L. Ying, Beijing HuaBei Optical Instrument Co., Ltd. (China)

Squarreness perpendicularity measuring techniques in multiaxis machine tools [7283-19]
A. W. Khan, W. Chen, Beihang Univ. (China)

Phase retrieval based wavefront sensing experimental implementation and wavefront sensing accuracy calibration [7283-20]
H. Mao, X. Wang, D. Zhao, Beijing Institute of Technology (China)

Interpolation circuit with high resolution and high response speed [7283-21]
W. Piao, Y. Yuan, L. Xu, H. Zhang, Harbin Institute of Technology (China)

POSTER SESSION

New method of fiber Bragg grating demodulation technique and applied in detection of equipment [7283-22]
B. Zhao, Z.-L. Zhang, Q.-Y. Zhong, H. Tu, L. Tan, Xi’an Research Institute of High Technology (China)
Three-beam coherent combination experiments based on segmented mirrors and measure of phase characteristics of beams passing through Yb-doped fiber amplifier [7283-23]

P. Yang, R. Yang, Institute of Optics and Electronics (China) and Graduate School of the Chinese Academy of Sciences (China); F. Shen, Institute of Optics and Electronics (China); M. Ao, Institute of Optics and Electronics (China) and Graduate School of the Chinese Academy of Sciences (China); W. Jiang, Institute of Optics and Electronics (China)

Development of photoelectric pulse laser range finding system [7283-24]

B. Tan, S. Wang, T. Li, F. Wen, Shandong Univ. of Technology (China)

Development of real-time photoelectric measurement on geometric size of objects [7283-25]

G. Yuan, T. Li, Shandong Univ. of Technology (China)

Study on surface topography of IBS oxide multilayer mirrors [7283-26]

Y. Chen, Northwestern Polytechnical Univ. (China); X. Zhang, F. Shan, B. Chen, Flight Automatic Control Research Institute (China)

Conjugate gradient optimum algorithm study of non-linear correction for one-dimension PSD [7283-27]

C. Mo, X. Du, L. Zhang, M. Wang, Harbin Univ. of Commerce (China)

Performance analysis of temperature and strain simultaneous measurement system based on coherent detection of Brillouin scattering [7283-28]

L. Zhao, Y. Li, J. Zhang, North China Electric Power Univ. (China)

Effect of threshold value on high reflectivity measurement with optical feedback cavity ring-down technique [7283-29]

Y. Gong, Institute of Optics and Electronics (China) and Graduate School of the Chinese Academy of Sciences (China); Y. Han, B. Li, Institute of Optics and Electronics (China)

Interfaces roughness cross correlation properties and light scattering of optical thin films [7283-30]

Y. Pan, Xi'an Univ. of Science and Technology (China) and Xidian Univ. (China); Z. Wu, Xidian Univ. (China); L. Hang, Xi'an Univ. of Science and Technology (China)

Quantitative measurement of optical surfaces using an improved knife edge [7283-31]

H. Jing, W. Yang, B. Fan, Y. Wan, S. Wu, F. Wu, T. Fan, Institute of Optics and Electronics (China)

Research on the measurement of large glass stress distribution [7283-32]

W. Yang, H. Jing, S. Wu, X. Cao, Institute of Optics and Electronics (China)

Model and simulation for testing two-mirror optical system by subaperture stitching interferometry [7283-33]

L. Wang, Institute of Optics and Electronics (China) and Graduate School of the Chinese Academy of Sciences (China); S. Wu, X. Hou, L. Kuang, X. Cao, Institute of Optics and Electronics (China)

Development of bubble tester [7283-34]

W. Yang, H. Jing, S. Wu, X. Cao, Institute of Optics and Electronics (China)
<table>
<thead>
<tr>
<th>Page</th>
<th>Title</th>
<th>Authors</th>
</tr>
</thead>
<tbody>
<tr>
<td>7283</td>
<td>Study on portable optical 3D coordinate measuring system [7283-36]</td>
<td>T. Ren, Xiamen Univ. (China); J. Zhu, Tianjin Univ. (China); Y. Guo, Xiamen Univ. (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Large field F-θ laser scanning system [7283-37]</td>
<td>B. Shan, B. Guo, H. Niu, Shenzhen Univ. (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Design of 3D measurement system based on multi-sensor data fusion technique [7283-39]</td>
<td>W. Zhang, J. Han, X. Yu, Xi'an Technological Univ. (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Ultra-precise micro-motion stage for optical scanning test [7283-40]</td>
<td>W. Chen, J. Zhang, N. Jiang, Xiamen Univ. (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Study of photoacoustic Imaging based on DSPI [7283-41]</td>
<td>Z. Lin, Xiamen Univ. (China) and Putian College (China); X. Lu, C. Lin, R. Ye, Y. Huang, Xiamen Univ. (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Dynamic deformation measurement based on inverse projected fringe technique [7283-42]</td>
<td>W. Li, Q. Zhang, Y. Liu, Sichuan Univ. (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Research on Hartmann test for progressive addition lenses [7283-43]</td>
<td>L. Qin, J. Yu, Soochow Univ. (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Distortion measurement and calibration technology research of automatic observing and aiming optical system based on CCD [7283-44]</td>
<td>X. Yu, Q. Li, X. Shang, L. Nie, Xi'an Technological Univ. (China); J. Wu, Xi'an Institute of Applied Optics (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Study on control structure analysis and optimization of high-precision measurement platform for optical aspheric surface [7283-45]</td>
<td>X. Ke, Y. Guo, Z. Wang, Xiamen Univ. (China); J. Liu, Xiamen Univ. of Technology (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Aspheric mirror measurement based on fringe reflection [7283-46]</td>
<td>X. Su, Y. Tang, Y. Liu, Q. Zhang, L. Xiang, Sichuan Univ. (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Surface test of continuous phase plate with stitching technique [7283-48]</td>
<td>R. Zhang, Sichuan Univ. (China)</td>
</tr>
</tbody>
</table>
Determination of optical constants in the VUV range for fluoride thin films [7283-49]
C. Xue, Shanghai Institute of Optics and Fine Mechanics (China), Changshu Institute of Technology (China), and Univ. of Science and Technology of China (China); K. Yi, C. Wei, J. Shao, Z. Fan, Shanghai Institute of Optics and Fine Mechanics (China)

Storage and compression design of high speed CCD [7283-50]
X. Cai, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of the Chinese Academy of Sciences (China); L. Zhai, Changchun Institute of Optics, Fine Mechanics and Physics (China)

Research and fabrication of integrated optical chip in FOG [7283-51]
D. En, Tianjin Univ. (China) and Henan Polytechnic Univ. (China); K. Xu, C. Chen, Y. Cui, Tianjin Univ. (China); J. Wang, Y. Zhao, Q. Si, Henan Polytechnic Univ. (China)

Study on the measurement of image motion between sequential images based on optical correlator [7283-52]
C. Fan, Henan Univ. of Technology (China); Y. Li, Institute of Optics and Precision Mechanics (China); Y. Liang, N. Sun, Henan Univ. of Technology (China)

Adaptive algorithm of infrared target enhancement for target recognition of infrared detector [7283-53]
J. Guo, W. Liu, Xi'an Technological Univ. (China); J. Gao, Xi'an Institute of Applied Optics (China); W. Qin, Xi'an Technological Univ. (China)

Fabry-Perot fiber pressure sensor based on white light interferometry and intensity demodulation method [7283-54]
Z. Guo, W. Li, Nankai Univ. (China); D. Zhang, Academy of Military Transportation (China); Y. Pan, Q. Meng, G. Liu, F. Ge, Nankai Univ. (China); X. Zhang, Academy of Military Transportation (China)

Study on adjustment technique of optical-axis parallelism in multibeam axes optoelectronic system [7283-55]
J. Han, J. Wang, Xi'an Technological Univ. (China); W. Chen, Xi'an Institute of Applied Optics (China); X. Yu, Xi'an Technological Univ. (China)

Application of wavelet analysis on thin-film wideband monitoring system [7283-56]
J. Han, Xidian Univ. (China) and Xi'an Technological Univ. (China); S. Wang, X. Shang, Xi'an Technological Univ. (China); Y. An, Xidian Univ. (China)

Study on the technology of sinusoidal phase modulating interferometry based on Fourier transform algorithm [7283-57]
G. He, Chongqing Normal Univ. (China) and Chongqing Univ. (China); M. Wu, S. Liu, L. Deng, Chongqing Normal Univ. (China)

Accuracy and error analysis of real-time surface profile measurement with sinusoidal phase modulation interferometer [7283-58]
G. He, Chongqing Univ. (China) and Chongqing Normal Univ. (China); H. Jiang, Chongqing Technology and Business Univ. (China); R. Liao, Chongqing Normal Univ. (China)
Research on vibration cancellation interferometric measurements of surface profile with nanometer accuracy [7283-59]
H. Jiang, Chongqing Technology and Business Univ. (China); G. He, Chongqing Normal Univ. (China)

Using translation invariant discrete wavelet transform to improve bias stability of fiber gyroscope [7283-60]
Y. Jia, C. Zhang, P. Ou, C. Li, L. Zhao, Beijing Univ. of Aeronautics and Astronautics (China)

Fiber Bragg grating dispersion measurement based on frequency domain processing [7283-61]
F. Jiang, Beijing Information Science and Technology Univ. (China); Q. Chen, Beijing Information Science and Technology Univ. (China) and Beijing Univ. of Post and Telecommunications (China)

Distortion correction of optical system based on neural network and automated generation of reference points [7283-62]
Q. Li, Huazhong Univ. of Science and Technology (China) and Wuhan Polytechnic Univ. (China); Y. Zeng, Z. Jiu, K. Yang, Huazhong Univ. of Science and Technology (China)

System study and error analysis of new photoelectricity film test [7283-63]
T. Li, S. Wang, F. Wen, B. Tan, Shandong Univ. of Technology (China)

Modeling and simulation research of a new calibration platform for visual test system [7283-64]
L. Bo, Y. Dong, R. Che, Harbin Institute of Technology (China)

Fluorescence detection system for mineral oil based on charge-coupled devices [7283-65]
J. Lv, Y. Wang, Z. Pan, Yanshan Univ. (China)

Measurement method in LLL equivalent eyepiece focus and error analysis [7283-66]
M. Miao, Y. Guo, Zhengzhou Institute of Aeronautical Industry Management (China)

Study on optimization of parameter selection in Fourier transform profilometry [7283-67]
J. Peng, L. Wang, X. Gao, Z. Wang, Q. Zhao, Southwest Jiatong Univ. (China)

Real-time compensation for interpolation error of Moiré fringes signal [7283-68]
W. Piao, Y. Yuan, F. Zhang, Harbin Institute of Technology (China)

Technique to transform optical deflection equations into linear difference ones for tomography [7283-69]
Y. Song, Nanjing Univ. of Aeronautics and Astronautics (China) and Dezhou Univ. (China); Z. Zhao, Nanjing Univ. of Aeronautics and Astronautics (China)

Laser-induced damage threshold detection for optical thin films and research on damage morphology [7283-70]
J. Su, J. Lou, Xi’an Technological Univ. (China)

Wave front reconstruction based on phase-shift fringe analysis [7283-71]
X. Su, W. Zhao, Q. Zhang, L. Xiang, Sichuan Univ. (China)
Dynamic evaluation system for interpolation errors in the encoder of high precision
[7283-72]
Q. Wan, Y. Wu, C. Zhao, L. Liang, Y. Sun, Y. Jiang, Changchun Institute of Optics, Fine
Mechanics and Physics (China) and Graduate School of the Chinese Academy of Sciences
(China)

Method for obtaining real temperature of space object by using the ratio of emissivity at
different wavelengths [7283-73]
G. Wang, Changchun Institute of Optics, Fine Mechanics and Physics (China) and
Graduate school of the Chinese Academy of Sciences (China); T. Chen, J. Wang,
Changchun Institute of Optics, Fine Mechanics and Physics (China)

Laser Doppler echo signal detection method [7283-74]
J. Wang, C. Zhang, D. Feng, P. Ou, L. Tian, Beihang Univ. (China)

Set of axes compensation and measurement between multitudinous photoelectric
instruments under shape changing carrier [7283-75]
J. Wang, Xi'an Technological Univ. (China); W. Chen, Xi'an Institute of Applied Optics
(China); J. Han, X. Yu, Xi'an Technological Univ. (China)

Novel FBG vibration sensor based on matching filter demodulation [7283-76]
J. Wang, Q. Sui, D. Feng, M. Jiang, Shandong Univ. (China)

Analysis on Chopper's output mode of the extended blackbody radiation calibration
system [7283-77]
X. Yu, Y. Wei, Xi'an Technological Univ. (China); T. Hu, Xi'an Institute of Applied Optics
(China); X. Shang, Xi'an Technological Univ. (China); J. Wu, Xi'an Institute of Applied Optics
(China)

Combining SVM and flame radiation to forecast BOF end-point [7283-78]
H. Wen, Q. Zhao, L. Xu, M. Zhou, Y. Chen, Nanjing Univ. of Science & Technology (China)

Method for recovering dynamic position of photoelectric encoder [7283-79]
Y. Wu, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate
School of the Chinese Academy of Sciences (China); Q. Wan, C. Zhao, Changchun Institute
of Optics, Fine Mechanics and Physics (China); Y. Sun, L. Liang, Changchun Institute of
Optics, Fine Mechanics and Physics (China) and Graduate School of the Chinese Academy
of Sciences (China); Y. Liu, National Ctr. of Quality Supervision and Inspection of Automobile
Spare Parts (China)

Adaptive tracking and compensation of laser spot based on ant colony optimization
[7283-80]
L. Yang, Xi'an Univ. of Technology (China) and Xi'an Technological Univ. (China); X. Ke, Xi'an
Univ. of Technology (China); R. Bai, Xi'an Technological Univ. (China); Q. Hu, Xi'an Univ. of
Technology (China)

Study on energy loss compensation of back scattering conical cavity high-energy laser
energy meter [7283-81]
X. Yu, H. Wang, X. Shang, L. Nie, B. Liu, Xi'an Technological Univ. (China)
Part Two

Study on direction detection of automobile headlamp beam [7283-82]
Y. Yun, S. Dai, P. Mu, L. Wang, Univ. of Shanghai for Science and Technology (China)

Analysis of polarimetric characteristics of camouflage targets [7283-83]
Z. Zhang, H. Cheng, Z. Chen, W. Zheng, National Univ. of Defense Technology (China)

Analysis of confocal readout signal in multilayer optical storage with vector diffraction theory [7283-84]
X. Gao, J. Zhang, W. Yang, Y. Hong, G. Jiang, Xiamen Univ. (China)

Real-time motive vehicle detection with adaptive background updating model and HSV colour space [7283-85]
R. Zhang, Y. Bai, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of the Chinese Academy of Sciences (China); H. Jia, T. Chen, Changchun Institute of Optics, Fine Mechanics and Physics (China)

Experimental study of alignment method for a positive-branch confocal unstable resonator based on H-S wavefront sensor [7283-86]
X. Zhang, Q. Cai, A. Xiang, Chengdu Univ. of Information Technology (China)

Researches on image processing arithmetic for draw-out the wheel profile from a light-section image [7283-87]
Y. Zhang, L. Wang, X. Gao, Q. Zhao, Z. Wang, Southwest Jiaotong Univ. (China)

Calibration of double ball bar (DBB) system [7283-88]
A. W. Khan, F. Liu, W. Chen, Beihang Univ. (China)

Sinusoidal phase modulating interferometer for real-time surface profile measurement [7283-89]
X.-W. Tan, Southwest Univ. (China) and Chongqing Univ. (China); G.-T. He, Chongqing Normal Univ. (China) and Shanghai Hengyi Optics & Fine Mechanics Co., Ltd (China)

Test of an off-axis asphere by subaperture stitching interferometry [7283-90]
X. Wang, L. Zheng, Changchun Institute of Optics, Fine Mechanics and Physics (China); B. Zhang, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of the Chinese Academy of Sciences (China); R.-G. Li, D. Fan, Changchun Institute of Optics, Fine Mechanics and Physics (China); W. Deng, X. Wang, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of the Chinese Academy of Sciences (China); F. Zhang, Z. Zhang, X. Zhang, Changchun Institute of Optics, Fine Mechanics and Physics (China)

Interferometric measurement method of thin film thickness based on FFT [7283-91]
G. Shuai, J. Su, L. Yang, J. Xu, Xi'an Technological Univ. (China)

Spectroscopic ellipsometry studies on vacuum-evaporated zinc selenide thin film [7283-92]
W. Gao, Institute of Optics and Electronics (China)
Study of online 3D vision coordinate measuring system for large-scale equipments [7283-93]
Q. Xu, Henan Univ. of Science and Technology (China); R. Che, Harbin Institute of Technology (China)

Research on laser spectrographic to detect CH4 system [7283-94]
M. Zhou, Anhui Univ. of Science and Technology (China)

Quantitative measurement of \( \Phi\)140mm F/2 parabolic surface with Ronchi grating test method [7283-95]
B. Lei, Institute of Optics and Electronics (China) and Graduate School of the Chinese Academy of Sciences (China); F. Wu, Institute of Optics and Electronics (China); C. Zhou, Yantai Univ. (China)

Research on registration algorithm based on feature points for human eye retina images [7283-96]
Y. Liu, Institute of Optics and Electronics (China) and Graduate School of the Chinese Academy of Sciences (China); H. Yang, Huaihai Institute of Technology (China); L. Su, Chongqing Institute of Technology (China); Y. Zhang, X. Rao, Institute of Optics and Electronics (China)

Defect study on several fluoride coatings [7283-97]
Y. Zhang, Y. Zhang, Institute of Optics and Electronics (China)

Analysis and study of zero displacement quantities of low-level light sight device based on shooting experimental condition [7283-98]
Y. Gao, Nanjing Univ. of Science & Technology (China) and NanYang Institute of Technology (China); Y. Xu, NanYang Institute of Technology (China); S. Tian, Nanjing Univ. of Science & Technology (China) and NanYang Institute of Technology (China); B. Chang, Nanjing Univ. of Science & Technology (China)

Measurement of 850nm waveband up-conversion characters based on Er\(^{3+}\)-doped silica fiber [7283-99]

Mathematical model of contacting aspheric surface profile measurement [7283-100]
G. Qiu, Soochow Univ. (China)

Optical flow detection based on enhanced fuzzy clustering with elastic grouping logic [7283-101]
Y. Lu, J. Zhang, Institute of Optics and Electronics (China) and Graduate Univ. of the Chinese Academy of Sciences (China); Y. Zhang, Chongqing Technology and Business Univ. (China); Q. Wu, Institute of Optics and Electronics (China)

Multi-sensor data fusion based on electro-optical tracking system [7283-102]
J. Zhang, Y. Lu, Institute of Optics and Electronics (China) and Graduate Univ. of the Chinese Academy of Sciences (China); W. Wang, Graduate Univ. of the Chinese Academy of Sciences (China) and Institute of Optics and Electronics (China); Y. Zhang, Institute of Optics and Electronics (China) and Graduate Univ. of the Chinese Academy of Sciences (China); Q. Wu, Institute of Optics and Electronics (China)
| 7283 2W | **Evaluation of dim target detection and tracking algorithms** [7283-103] |
| ——— | ——— |
| | Y. Zhang, Institute of Optics and Electronics (China), Graduate School of the Chinese Academy of Sciences (China), and Chongqing Technology and Business Univ. (China); M. Xiong, Institute of Optics and Electronics (China) and Graduate School of the Chinese Academy of Sciences (China); Q. Wu, Institute of Optics and Electronics (China) |

| 7283 2X | **Study on a reference detection of infrared thermograph with high precision** [7283-104] |
| ——— | ——— |
| | Y. Xu, M. Cao, K. Xu, Shandong Univ. of Science and Technology (China) |

| 7283 2Y | **Method of circle detection in PCB optics image based on improved point Hough transform** [7283-105] |
| ——— | ——— |
| | N. Qiao, Univ. of Electronic Science and Technology of China (China) and Hunan Univ. of Arts and Science (China); Y. Ye, Y. Huang, L. Liu, Y. Wang, Univ. of Electronic Science and Technology of China (China) |

| 7283 2Z | **Scientific CCD camera caused bias estimates of low-light-level quantitative fluorescence imaging measurement** [7283-106] |
| ——— | ——— |
| | Z. Hu, Wenzhou Univ. (China); J. Zhang, Hefei Univ. of Technology (China) |

| 7283 30 | **Research on the measurement of thin film thickness based on phaseshift interferometry** [7283-107] |
| ——— | ——— |
| | Y. Shi, J. Su, L. Yang, J. Xu, Xi'an Technological Univ. (China) |

| 7283 31 | **Extended target detection in complex background based on fractal theory** [7283-108] |
| ——— | ——— |
| | K. Zhang, Shenzhen Univ. (China); Q. Zhang, Institute of Optics and Electronics (China); X. Yang, Shenzhen Univ. (China) |

| 7283 32 | **New method for laser parameter detection** [7283-109] |
| ——— | ——— |
| | X. Zhang, Wuhan Institute of Technology (China); H. Hong, Wuhan Institute of Technology (China) and Huazhong Univ. of Science and Technology (China); H. Zhang, X. Wan, Wuhan Institute of Technology (China) |

| 7283 33 | **Research of crystal material birefringence measurement method** [7283-110] |
| ——— | ——— |
| | X. Wen, D. Zhao, Zhengzhou Institute of Aeronautical Industry Management (China) |

| 7283 34 | **Application of CCD measurement technique for wear on pantograph sliding plates** [7283-111] |
| ——— | ——— |
| | K. Yang, L. Wang, X. Gao, Q. Zhao, Z. Wang, C. Peng, Southwest Jiaotong Univ. (China) |

| 7283 35 | **Lens distortion rectifying in camera optical system using planar grid** [7283-112] |
| ——— | ——— |
| | X. Chen, X. Zhang, S. Guan, Northeast Dianli Univ. (China) |

| 7283 36 | **Novel method for stereo camera extrinsic calibration using 1D reference objects** [7283-113] |
| ——— | ——— |
| | Y. Huang, D. Ye, R. S. Che, Harbin Institute of Technology (China) |

| 7283 37 | **Iterative estimation of phase distribution on reference planes in grating projection profilometry** [7283-114] |
| ——— | ——— |
| | X. Zhang, B. Zhang, Tianjin Univ. of Technology (China); Y. Lin, Tianjin Univ. (China); D. Liu, X. Li, Tianjin Univ. of Technology (China) |
7283 38 Scattering property of rough surface of silicon solar cells [7283-115]
L. Bai, Xidian Univ. (China) and Xi'an Technological Univ. (China); Z. Wu, S. Tang, Xidian Univ. (China); Y. Pan, Xi'an Technological Univ. (China)

7283 39 Appropriate sampling quantity and its influence on particle sizing results in PCS technique [7283-116]
J. Shen, Y. Cheng, W. Liu, Y. Wang, Shandong Univ. of Technology (China)

7283 3A Micro-spectroscopy system based on common inverted microscope to measure UV-VIS spectra of a micro-area [7283-117]
A. Yang, Ocean Univ. of China (China); J. Zhang, Ocean Univ. of China (China) and Beijing Normal Univ. (China); W. Ren, M. Tang, Ocean Univ. of China (China)

7283 3B Novel photon correlator with less hardware resource [7283-118]
W. Liu, J. Shen, Y. Cheng, W. Chen, Shandong Univ. of Technology (China)

7283 3C Analysis of thermal effect and experimental measurement of output wavefront properties with all-solid-state Nd:YAG laser [7283-119]
X. Zhang, Q. Cai, A. Xiang, Chengdu Univ. of Information Technology (China)

7283 3D Principle of optical fiber on-line detecting system for roller wear and software imitation [7283-120]
Y. Guo, Qi Qihaer Univ. (China)

7283 3E Gas monitor technology of electrical modulation non-dispersion infrared sensor [7283-121]
Y. Chen, R. Guo, Zhengzhou Institute of Aeronautical Industry Management (China)

7283 3F Application of FTIR spectrometer to the test of extinction performance of water fog with infrared emission [7283-122]
X. Wang, Institute of Chemical Defense (China)

7283 3G Dispersed Rayleigh interferometer [7283-123]
S. Wang, Q. Zhu, G. Cao, Beijing Institute of Technology (China)

7283 3H Quality weight based on log modulation amplitude for fringe analysis during optical fringe measurement [7283-124]
Y. Zhu, S. Yin, Y. Fan, B. Lv, Hunan Univ. (China)

7283 3I 3-D reconstruction based on binocular stereo vision [7283-125]
F. Wang, S. Dai, Univ. of Shanghai for Science and Technology (China)

7283 3J Spectral-domain optical coherence tomography (SD-OCT) with a thermal light source [7283-126]
Y. Chen, H. Zhao, Z. Wang, C. Deng, B. Yu, Xi'an Jiaotong Univ. (China)

7283 3K Nonlinear filter algorithm for opto-electronic target tracking [7283-127]
M. Xiong, J. Song, Institute of Optics and Electronics (China) and Graduate School of the Chinese Academy of Sciences (China); Q. Wu, Institute of Optics and Electronics (China)
Application of fuzzy evidence theory in a photo-electric measurement system [7283-128]
J. Song, M. Xiong, J. Zhang, Institute of Optics and Electronics (China) and Graduate School of the Chinese Academy of Sciences (China); Q. Wu, Institute of Optics and Electronics (China)

Effect of modulation frequency on detecting defects of metal plates using infrared lock-in thermography [7283-129]
H. Liu, Y. Wang, J. Liu, H. Gong, Harbin Institute of Technology (China)

Research on vibration measurement of a cantilever beam by twin-core fiber [7283-130]
T. Geng, T. Liu, F. Peng, Q. Dai, Y. Yang, Harbin Engineering Univ. (China)

Research on testing method of wide distance optical axis parallelism [7283-131]
L. Zhang, L. Zhang, Y. Hu, Changchun Univ. of Science and Technology (China)

Digital holographic microscopy for quantitative phase-contrast imaging [7283-132]
H. Wang, R. Han, Z. Tang, Hebei Univ. of Engineering (China)

Autofocus method in digital holographic microscopy [7283-133]
J. Liu, X. Song, R. Han, H. Wang, Hebei Univ. of Engineering (China)

Reach on the measurement of the terminal performance of space laser communication system [7283-134]
Y. Hu, Y. Fu, Z. Liu, T. Gao, Changchun Univ. of Science and Technology (China)

Approximate model for calculating radiance of atmospheric background [7283-135]
C.-P. Yang, X. Q. Meng, J. Wu, Univ. of Electronic Science and Technology of China (China)

Research on collective cracks' strain field with digital real-time holography [7283-136]
R. X. Guo, H. T. Xia, Z. B. Fan, B. C. Yang, J. C. Li, T. C. He, Kunming Univ. of Science and Technology (China)

Technology for inspecting the end face of fiber connector based on digital micro-holography [7283-137]
Y. Shen, X. Wan, H. Wang, H. Jin, B. Peng, Zhejiang Normal Univ. (China)

Study on demodulating wide range off-centering of distributed FBG by AWG [7283-138]
X. Wan, B. Peng, Y. Shen, H. Jin, Zhejiang Normal Univ. (China)

Research on optical measurement technology of optical multifilament basic parameters [7283-139]
G. Zhou, J. Wang, Harbin Normal Univ. (China)

Research on parallel processing for star acquirement and star identification [7283-140]
G. Zhou, L. Sheng, Harbin Normal Univ. (China)

Image analysis of complex patterns in nonlinear optical system [7283-141]
F. Liu, Y. Ha, X. Wang, Hebei Univ. (China)
<table>
<thead>
<tr>
<th>Page</th>
<th>Title</th>
<th>Authors</th>
</tr>
</thead>
<tbody>
<tr>
<td>7283</td>
<td>Novel detection system for micro-strain signal based on demodulation method of tilted fiber Bragg grating sensors</td>
<td>B. Peng, Y. Shen, C. Ying, X. Wan, Y. Zhu, H. Ye, Zhejiang Normal Univ. (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Comparison of three basic reconstruction algorithms in digital holography</td>
<td>X. Song, B. Zhao, A. Qin, Hebei Univ. of Engineering (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Analysis of working range in IR camera measurement</td>
<td>W. Dong, J. Chen, Y. An, Xi'an Technological Univ. (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Miniaturized broad-banded luminous source with fiber output for spectrophotometer</td>
<td>L. Zhu, W. Yang, Z. Huang, J. Zhang, Y. Huang, Xiamen Univ. (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Experimental study of laser beam propagation in turbulent atmosphere</td>
<td>C.-P. Yang, W.-G. He, J. Wu, Univ. of Electronic Science and Technology of China (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Efficient auto-focus algorithm for optical measurement system</td>
<td>J. Ni, China Jiliang Univ. (China); M. Wei, Chengdu Univ. of Information Technology (China); J. Yuan, Q. Wu, Institute of Optics and Electronics (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Auto-focusing technology for photoelectric measurement system</td>
<td>T. Lei, Institute of Optics and Electronics (China) and Graduate Univ. of the Chinese Academy of Sciences (China); S. Yang, Chengdu Univ. of Technology (China); Y. Zhang, Graduate Univ. of the Chinese Academy of Sciences (China); Q. Wu, Institute of Optics and Electronics (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Optimization of 3-D topography measurement based on Moiré technique</td>
<td>L. Nie, J. Han, X. Yu, B. Liu, Xi'an Institute of Technology (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Image denoising based on wavelet transform</td>
<td>Y. Ha, Hebei Univ. (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Study on bi-color phase measurement deflectometry</td>
<td>Y. Liu, X. Su, Q. Zhang, Sichuan Univ. (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Research of measuring instrument with freeform surface</td>
<td>Y. Wang, Wenzhou Medical College (China) and Ministry of Health (China); J. Yu, Wenzhou Medical College (China) and Soochow Univ. (China); Y. Ni, Soochow Univ. (China); J. Qu, H. Chen, Wenzhou Medical College (China) and Ministry of Health (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Study on measuring vibration displacement by shear interference based on sinusoidal phase modulation</td>
<td>G. He, F. Tang, Chongqing Normal Univ. (China); L. Song, Chongqing Normal School Hospital (China); H. Jiang, Chongqing Technology and Business Univ. (China)</td>
</tr>
<tr>
<td>7283</td>
<td>Study on interferometric measurements of a high accuracy laser-diode interferometer with real-time displacement measurement and its calibration</td>
<td>Y. Zeng, Chongqing Normal Univ. (China); G. He, Chongqing Normal Univ. (China) and Chongqing Univ. (China)</td>
</tr>
</tbody>
</table>
Test of vertex radius and conic constant of a conic surface by means of interferometry [7283-155]
G. Wu, Institute of Optics and Electronics (China) and Graduate School of the Chinese Academy of Sciences (China); Q. Chen, X. Hou, Graduate School of the Chinese Academy of Sciences (China)

Application research of machine vision in LCD panel flaw detection [7283-156]
C. Xie, X. H. Jin, S. Dai, Univ. of Shanghai for Science and Technology (China)

Modeling and analysis of optical test of digital camera based on orthoperspective theory [7283-157]
W. Zhang, J. Qiu, X. Liu, Shanghai Univ. of Engineering Science (China)

Layered fast correlation tracking algorithm combined with target feature [7283-158]
Y. Bai, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of the Chinese Academy of Sciences (China); H. Jia, L. Guo, Changchun Institute of Optics, Fine Mechanics and Physics (China); R. Zhang, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of the Chinese Academy of Sciences (China)

Research on focal length determination technique of laser test system based on Talbot effect [7283-159]
L. Wu, Xi'an Institute of Optics and Precision Mechanics (China), Graduate School of the Chinese Academy of Sciences (China), and Xi'an Technological Univ. (China); L. Zheng, Henan Institute of Metrology (China); G. Wu, Xi'an Institute of Optics and Precision Mechanics (China); Y. Cang, Xi'an Institute of Optics and Precision Mechanics (China) and Graduate School of the Chinese Academy of Sciences (China); L. Chen, Xi'an Institute of Optics and Precision Mechanics (China)

Ceramic substrate's detection system based on machine vision [7283-160]
L. Yang, Z. Zhou, L. Zhu, Jiaxing Univ. (China)

Evaluation method of circular optical surfaces through power spectral density [7283-161]
W. Chen, Xi'an Univ. of Science and Technology (China)

Study on location method with testing interferometric data of circle optical components [7283-162]
W. Chen, G. Zhou, Y. Ju, Xi'an Univ. of Science and Technology (China); B. Fan, Y. Wan, Institute of Optics and Electronics (China)

Novel method for measuring diameter of large-scale mirrors [7283-163]
T. Sun, Institute of Optics and Electronics (China) and Graduate School of the Chinese Academy of Sciences (China); L. Yang, Y. Wu, Institute of Optics and Electronics (China)

Analysis of real-time performance of stereo matching algorithm vision [7283-164]
P. Li, Harbin Normal Univ. (China)

New algorithm of mesh simplification based on the gradient of curvature [7283-165]
Q. Wu, F. Yang, Shenzhen Univ. (China)
Research of fitting algorithm for coefficients of rotational symmetry aspheric lens [7283-166]
Z. Chen, Z. Guo, Q. Mi, Z. Yang, R. Bai, Xi'an Technological Univ. (China)

Author Index
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